

**Notice of References Cited**

Application/Control No.

10/560,208

Applicant(s)/Patent Under  
Reexamination  
UENO ET AL.

Examiner

ANABEL M. TON

Art Unit

2875

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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	C	US-			
	D	US-			
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**FOREIGN PATENT DOCUMENTS**

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	N	JP 2002133906 A	05-2002	Japan	ONISHI et al.	
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**NON-PATENT DOCUMENTS**

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